

Produced & Distributed by AST, Inc.

# AST-M200C

## Features & Specifications:

- Meant as an aid to find defects either visually or thermo-graphically with the MWIR band (3-5 microns)
- Thermo graphic microscope to find thermally identifiable defects
- Applications for Aerospace, Medical Device, Semiconductor and Forensic; materials / process development and analysis
- Magnifications from Macro to 1x, 2.5x, 4x and 5x
- Precision 0.10 micron resolution 200mm travel motorized stage for accurate navigation and metrology
- Stage has 6mm cross-roller, lead-screw/stepper motor construction and can accommodate heavy loads (up to approximately 25 kilos)
- Precision 0.10 micron Z axis 250mm travel motorized column for sample and tooling compatibility and Z axis metrology
- Thermal detection to 20 mK
- Spatial resolution below 10 microns 640 x 512, 20 micron pixel
- InSb FPA on a closed cycle dewar (no LN2 required)
- Self-contained work station with probe platforms on both sides of stage
- System includes various image analysis and enhancement features
- System includes image stitching for large sample, high resolution work
- A host of options and configuration are available and systems can be custom built for your applications



The **AST-M200C** is a new Mid Wave Infrared Microscope for defect detection and analysis. Universal configuration for a multitude of applications. Powerful software included.



## Autocollimator

Compact & Powerful  
Precision Angle  
Measurement System

A highly flexible system packed with features not available from other attitude measurement systems.



## AST-200

Advanced Defect  
Inspection & Metrology  
System

Designed for applications where high-speed defect detection and precision measurements are required.



## AST-M200C

Mid Wave Infrared  
Inspection System

Mid Wave Infrared platform designed for defect detection, analysis, and thermography on wafers, die, devices, and more.



## AST-230M

Ergonomic Metrology  
Workstation

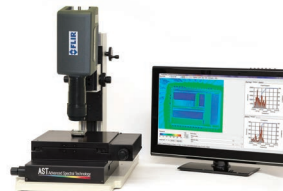
An easy to use metrology workstation with a range of recipe controlled illuminations.



## AST-S200T

Short Wave Infrared  
Microscope  
Bench Top System

Designed for materials transparent to the Near Infrared (NIR) / Shortwave Infrared (SWIR) wavelengths.



## AST-M150T

Mid Wave Infrared  
Microscope for Defect  
Detection and Analysis

Mid Wave Infrared Bench Top Microscope for defect detection, analysis, and thermography.



## Setna Ontos7

Atmospheric Plasma for  
Surface Preparation



Ontos7 provides a rapid atmospheric process which reduces surface contaminates.



## AST Services:

- Service all brands and styles, Preventative and repair
- Calibrate most instruments and systems
- Training your staff on proper operation and techniques
- Upgrading for Digital Imaging, Analysis, Illumination Techniques, etc.
- Application Specialists, Let us help you figure out how to do what you need for your process, procedure, Metrology and/or inspection requirements!